

Beam-spin asymmetry of Deeply Virtual Compton Scattering off the proton at 10.6 GeV with CLAS12 at Jefferson Lab

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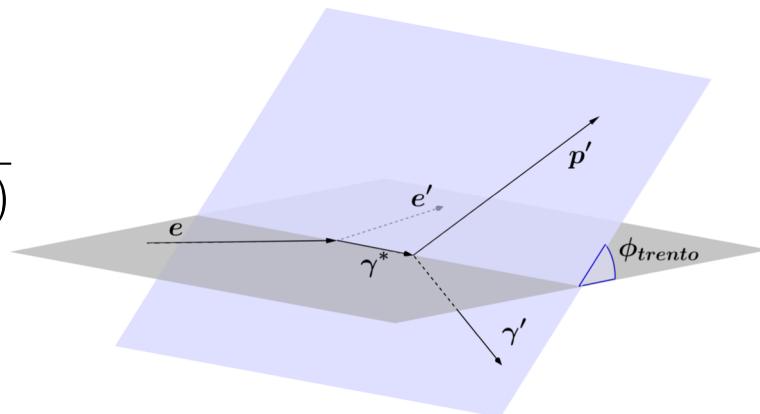
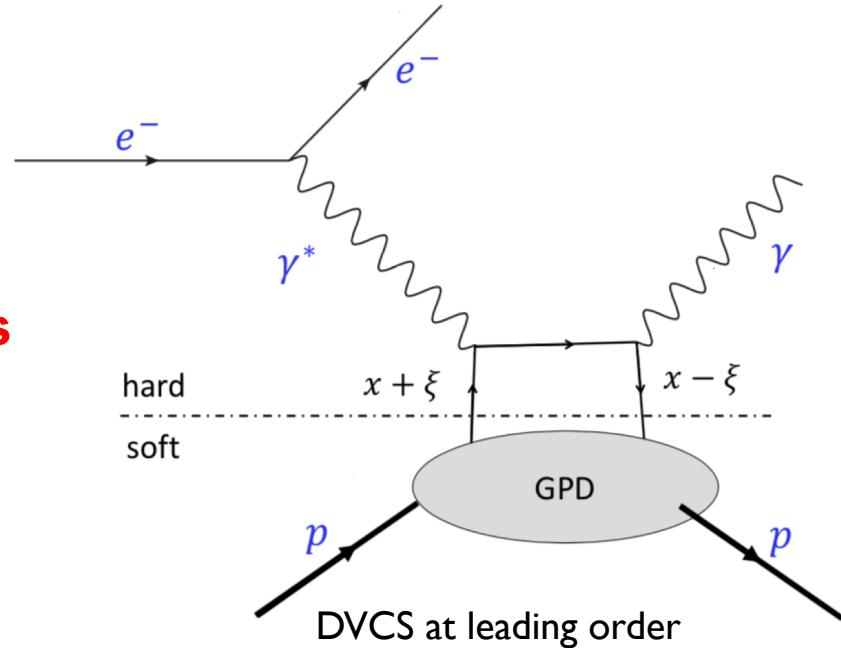
DVCS BSA to access GPDs

Deeply Virtual Compton Scattering

- Factorization:
 - hard scattering perturbative part
 - soft part parametrized by
Generalized Parton Distributions
inside Compton Form Factors

DVCS Beam-spin asymmetry

- BSA: $A_{LU} = \frac{d\sigma^{\uparrow} - d\sigma^{\downarrow}}{d\sigma^{\uparrow} + d\sigma^{\downarrow}}$
- ϕ harmonic expansion of the amplitude
- First order BSA: $A_{LU} \simeq \frac{A \sin(\phi_{trento})}{1 + B \cos(\phi_{trento})}$
- Mainly sensitive to GPD H
 $A \propto \sim \text{Im}(\mathcal{H})$ and $B \propto \sim \text{Re}(\mathcal{H})$



DVCS Analysis Overview

Analysis steps:

- 0 - Pre-selection of events
- 1 - Kinematic binning
- 2 - Selection of exclusive DVCS events
- 3 - Background subtraction (π^0 electroproduction)
- 4 - Bin migration correction
- 5 - Estimation of uncertainties
- 6 - Results

Fall 2018 RG-A
inbending 10.6 GeV
data

but can be easily
applied to the rest of
data

0 - Pre-selection of events

0 - Pre-selection of events

Particles from event builder

- High energy **electron**

$$E_{electron} > 2 \text{ GeV}$$

- High energy **photon**

$$E_{photon} > 2 \text{ GeV}$$

- **Proton**

To deal with combinatorics:

- Remove events with more than 1 electron
- Selection of best proton and best photon candidates based their “distance” to an ideal DVCS event (using exclusivity variables)

Kinematic variables:

- Virtuality

$$Q^2 = -q^2 > 1 \text{ GeV}^2$$

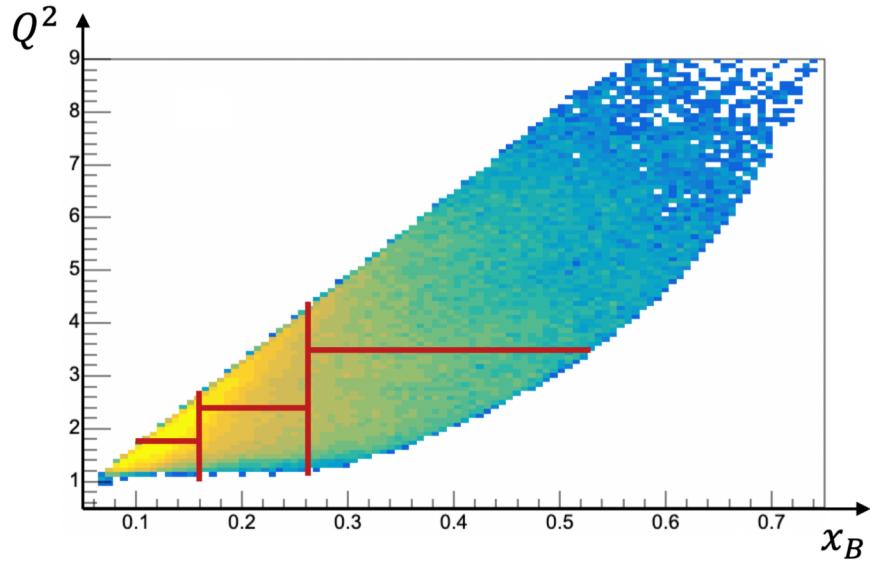
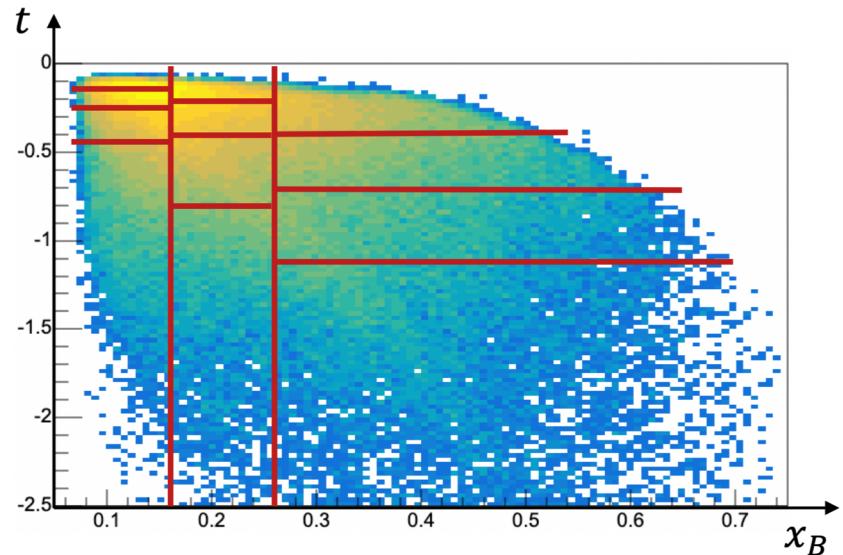
- Squared invariant mass of proton and photon
$$W^2 = (p + q)^2 > 4 \text{ GeV}^2$$

1 - Kinematic binning

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Choice of binning

- 4 t bins
 - 3 x_B bins
 - 2 Q^2 bins
 - 10 ϕ_{trento} bins
- } 24 bins

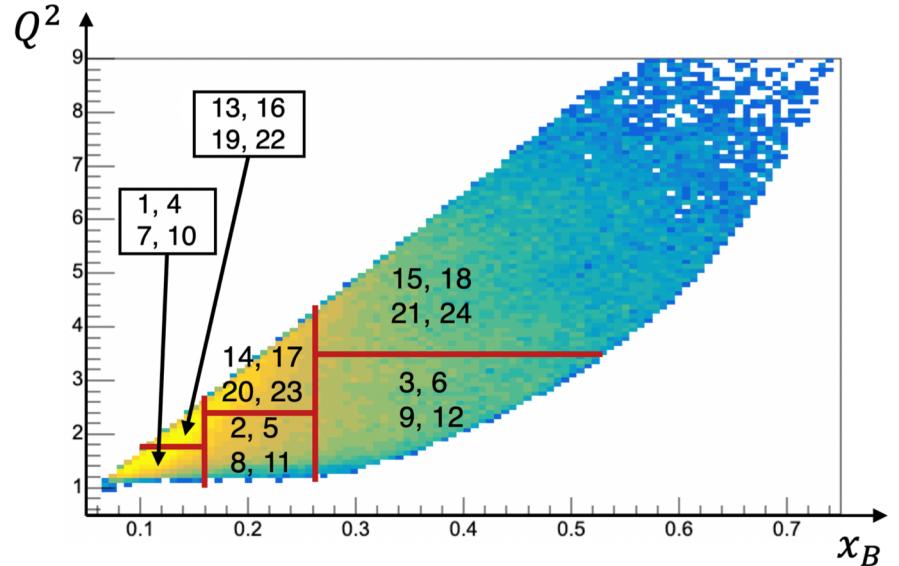
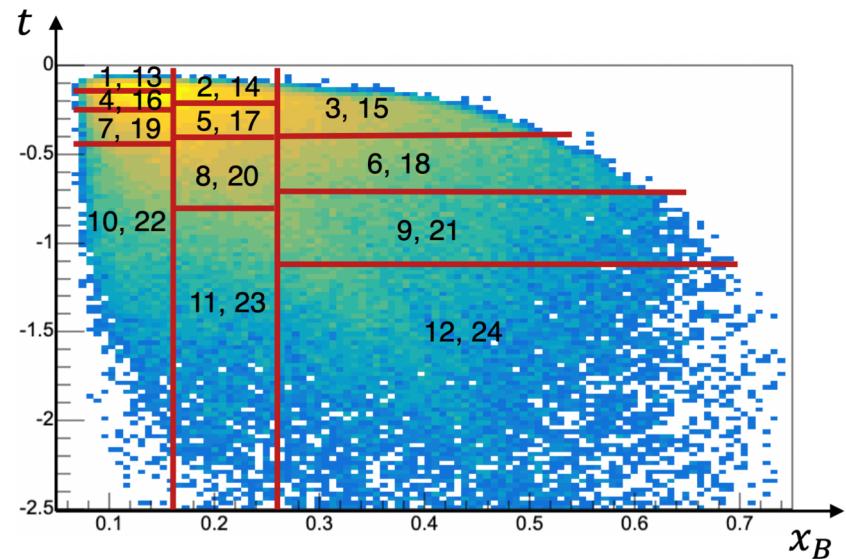


1 - Kinematic binning

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Choice of binning

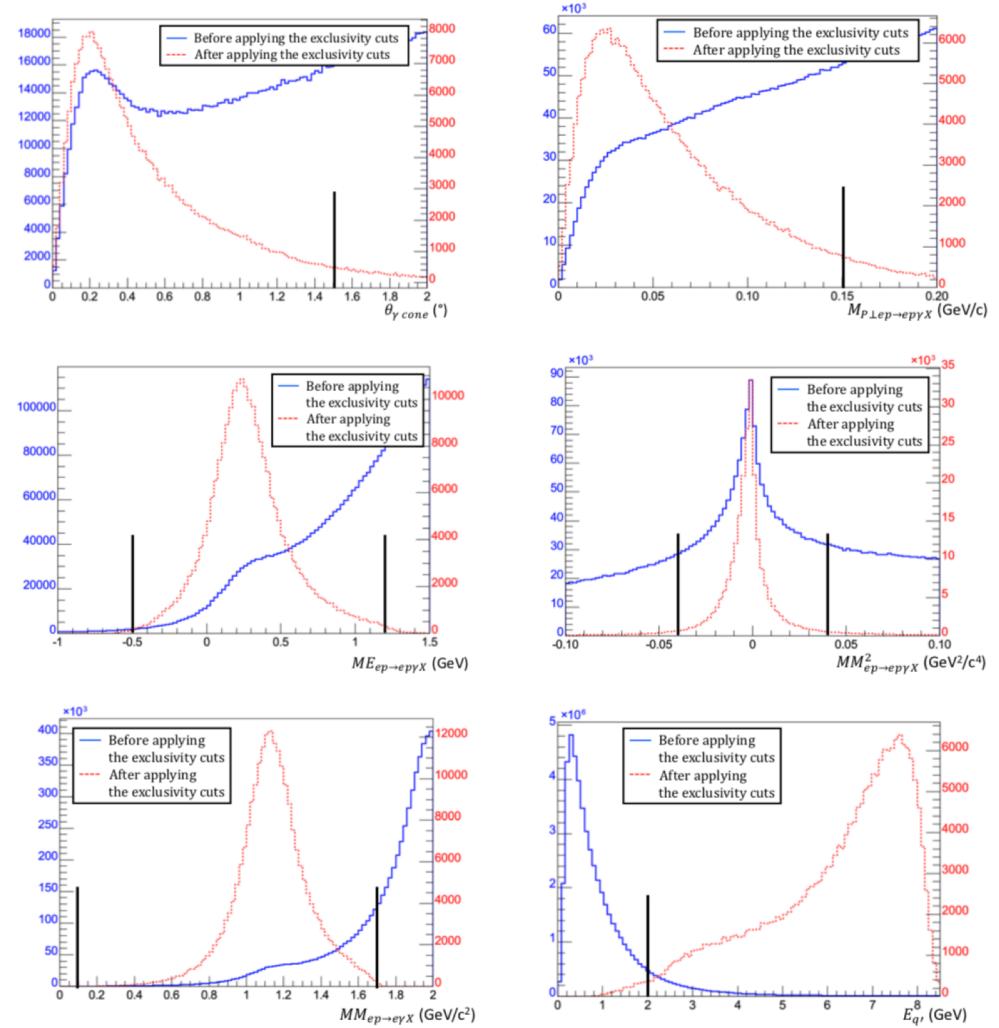
- 4 t bins
- 3 x_B bins
- 2 Q^2 bins
- 10 ϕ_{trento} bins



2 - Selection of exclusive DVCS events

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- **Photon cone angle**
(angle between measured photon and exclusive missing photon)
- **Missing transverse momentum** $ep \rightarrow e\gamma\gamma X$
- **Missing energy** $ep \rightarrow e\gamma\gamma X$
- **Squared missing mass** $ep \rightarrow e\gamma\gamma X$
- **Missing mass** $ep \rightarrow e\gamma X$
- **Photon energy**



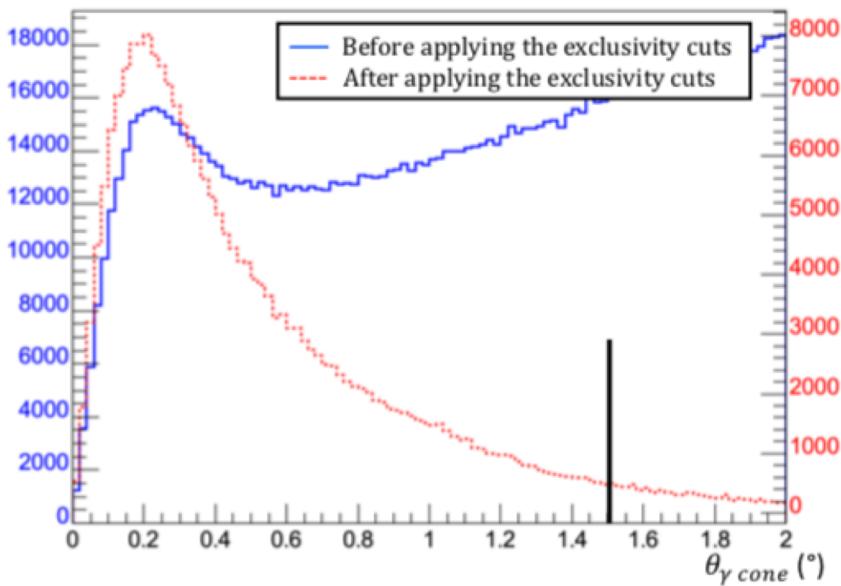
2 - Selection of exclusive DVCS events

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- **Photon cone angle**

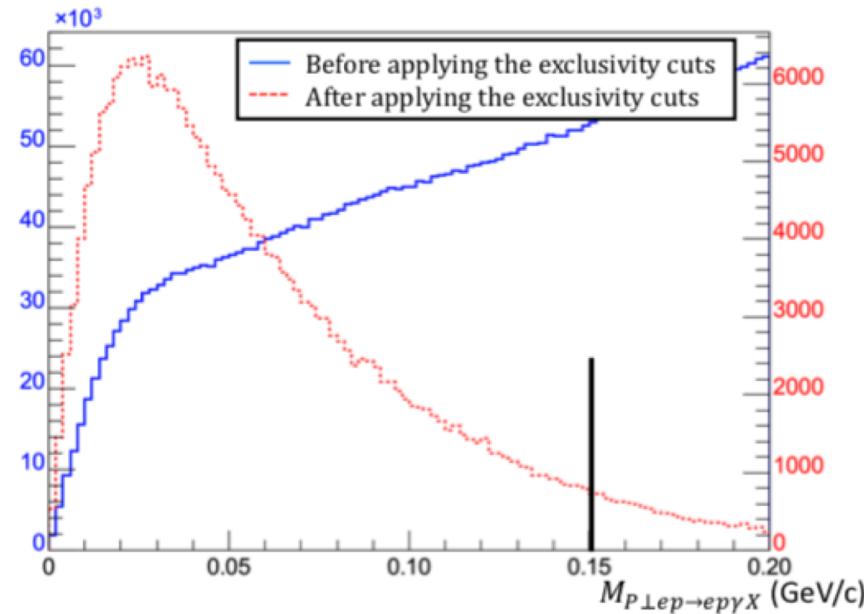
(angle between measured photon and exclusive missing photon)

$$\theta_{\gamma \text{ cone}} < 1.5^\circ$$



- **Missing transverse momentum** $ep \rightarrow ep\gamma X$

$$M_{p\perp ep \rightarrow ep\gamma X} < 0.15 \text{ GeV}/c$$

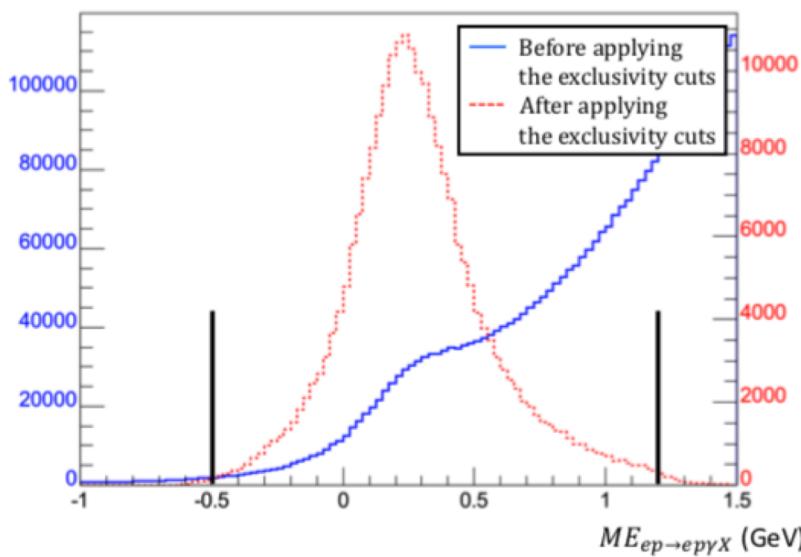


2 - Selection of exclusive DVCS events

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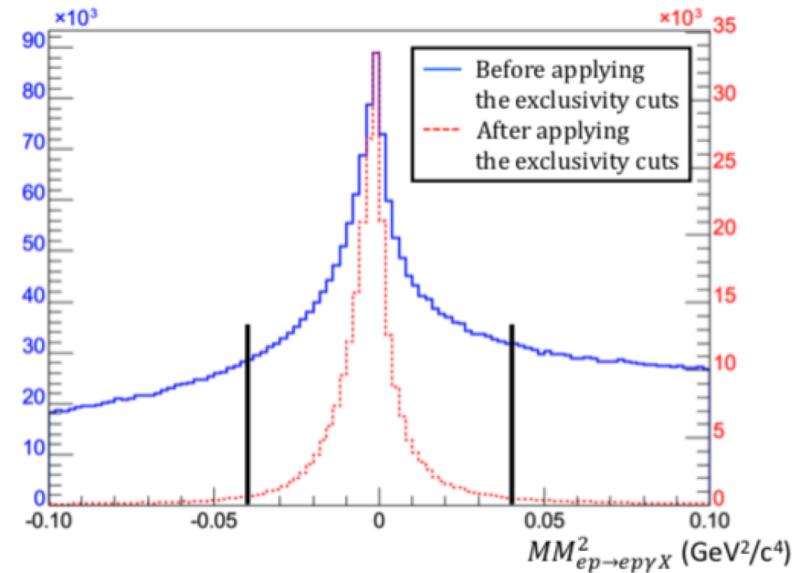
- **Missing energy** $ep \rightarrow ep\gamma X$

$$-0.5 \text{ GeV} < ME_{ep \rightarrow ep\gamma X} < 1.2 \text{ GeV}$$



- **Squared missing mass** $ep \rightarrow ep\gamma X$

$$-0.04 \text{ GeV}^2/c^4 < MM_{ep \rightarrow ep\gamma X}^2 < 0.04 \text{ GeV}^2/c^4$$

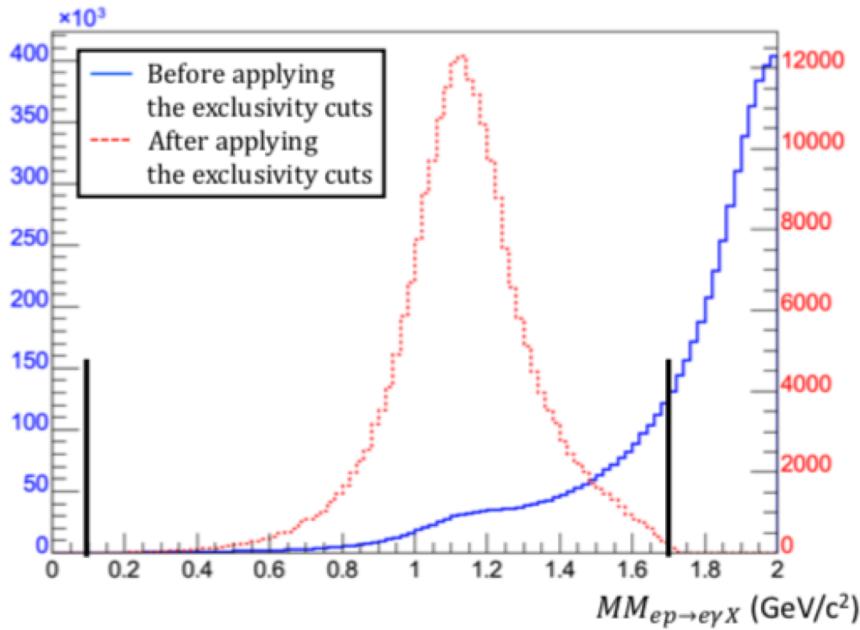


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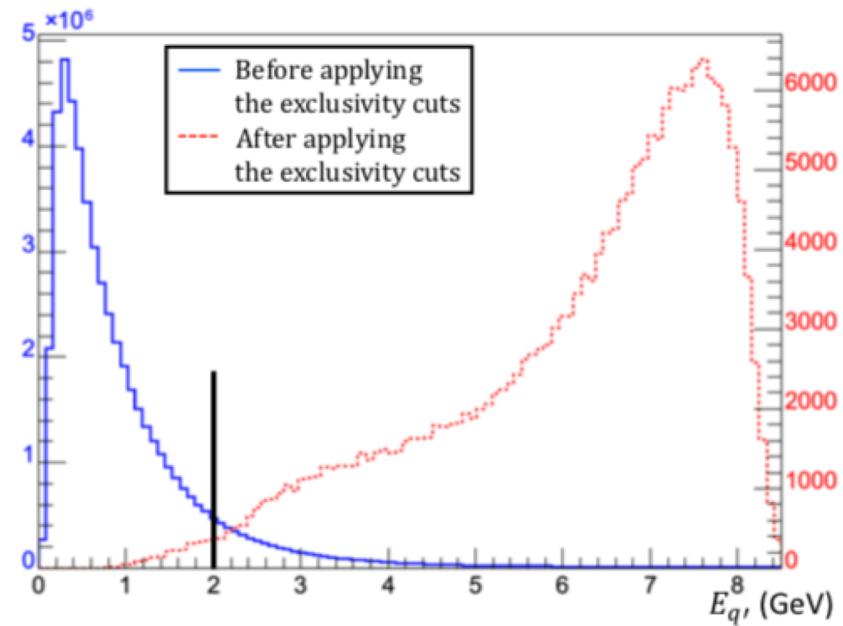
- **Missing mass** $ep \rightarrow e\gamma X$

$$0.1 \text{ GeV}/c^2 < MM_{ep \rightarrow e\gamma X} < 1.7 \text{ GeV}/c^2$$



- **Photon energy**

$$E'_q > 2 \text{ GeV}$$

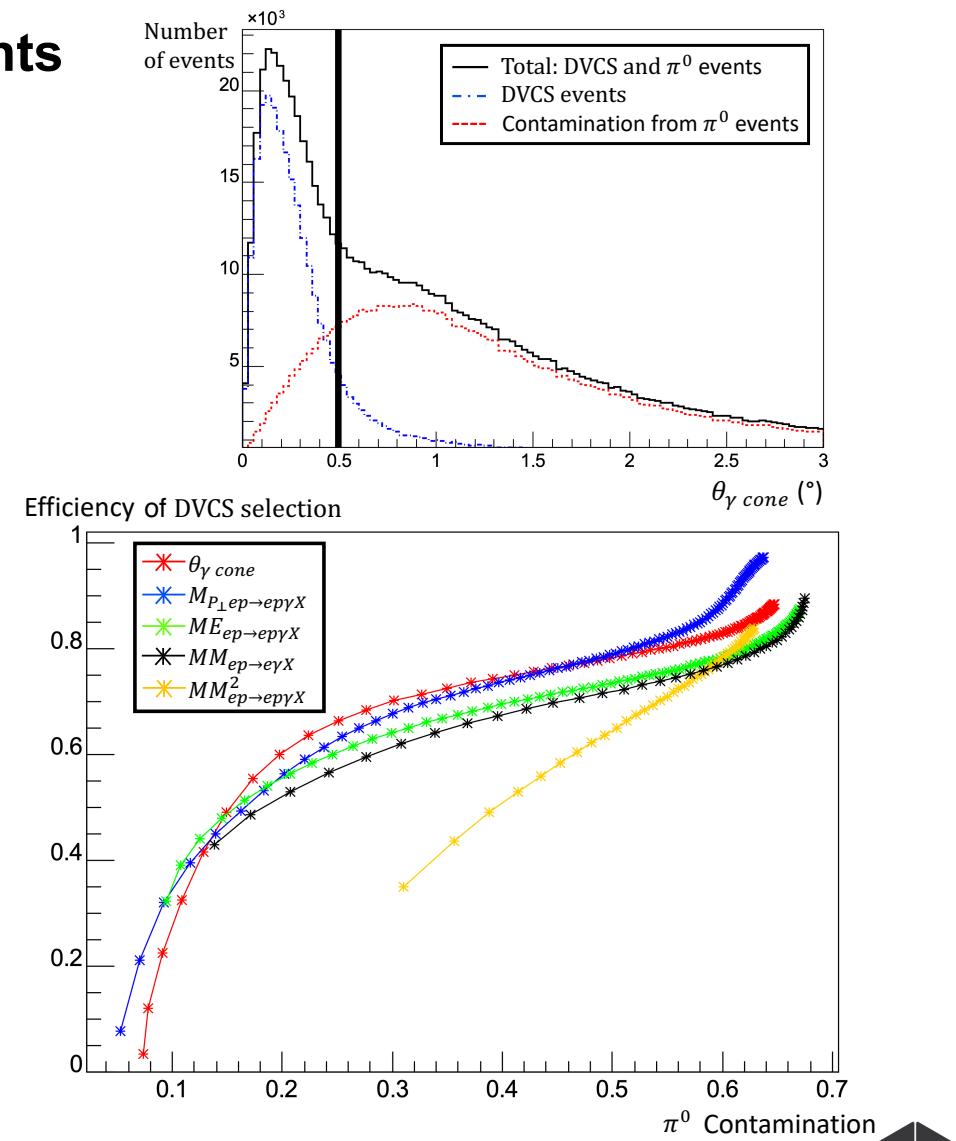


2 - Selection of exclusive DVCS events

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Optimization of the DVCS exclusivity selection based on the contamination

- **Identify the most discriminating variables in a DVCS + π^0 simulation**
- Optimize the position of the cut to minimize the statistical uncertainty DVCS + π^0
- Adapt the position of the cuts from simulation to “data” based on the resolution

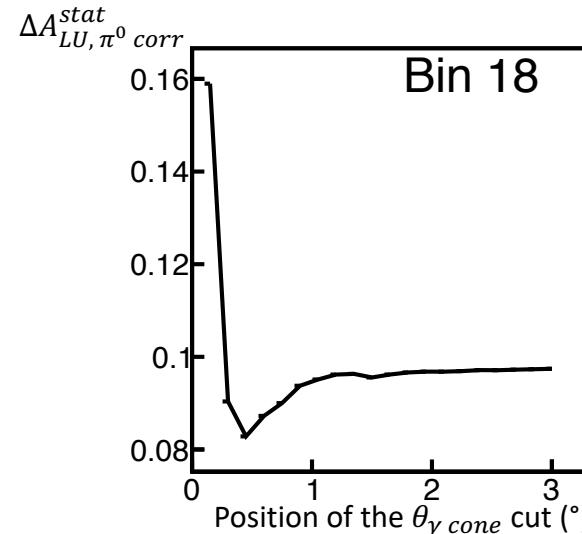
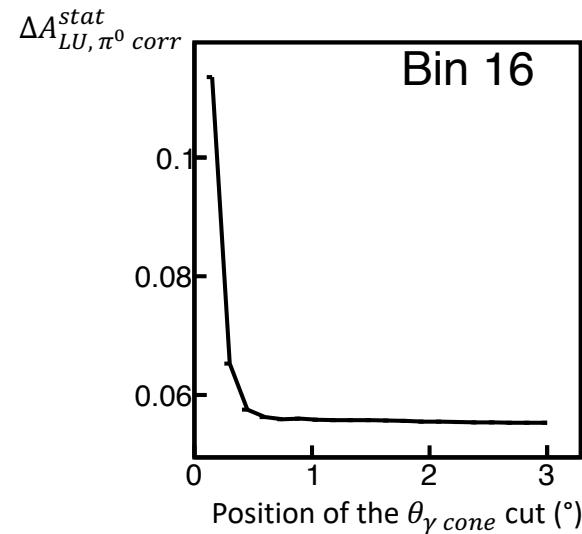


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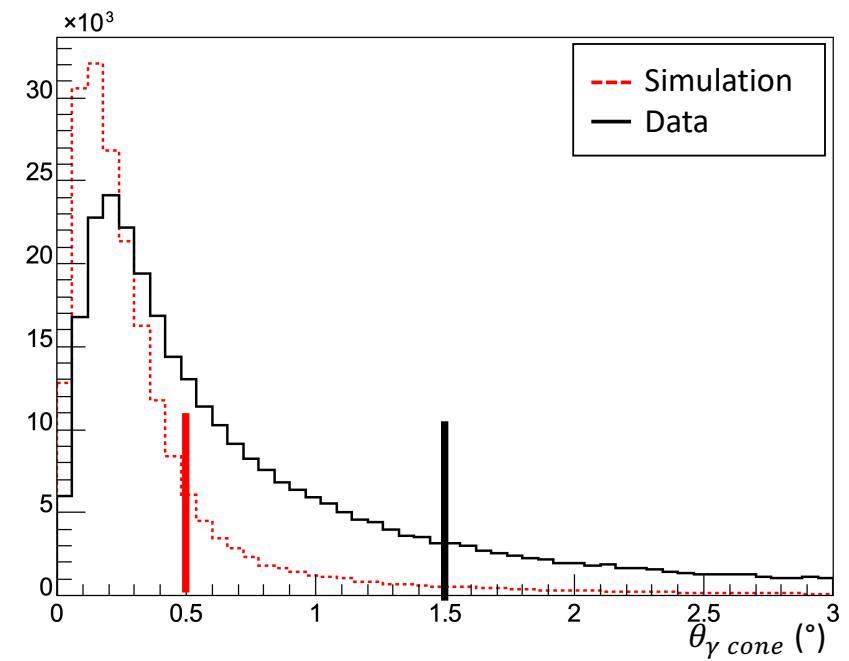


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- **Adapt the position of the cuts from simulation to “data” based on the resolution**



First look at beam-spin asymmetry

Raw asymmetry after DVCS selection (no background subtraction):

BSA for each bin:

$$A_{LU} = \frac{1}{P} \frac{N^+ - N^-}{N^+ + N^-}$$

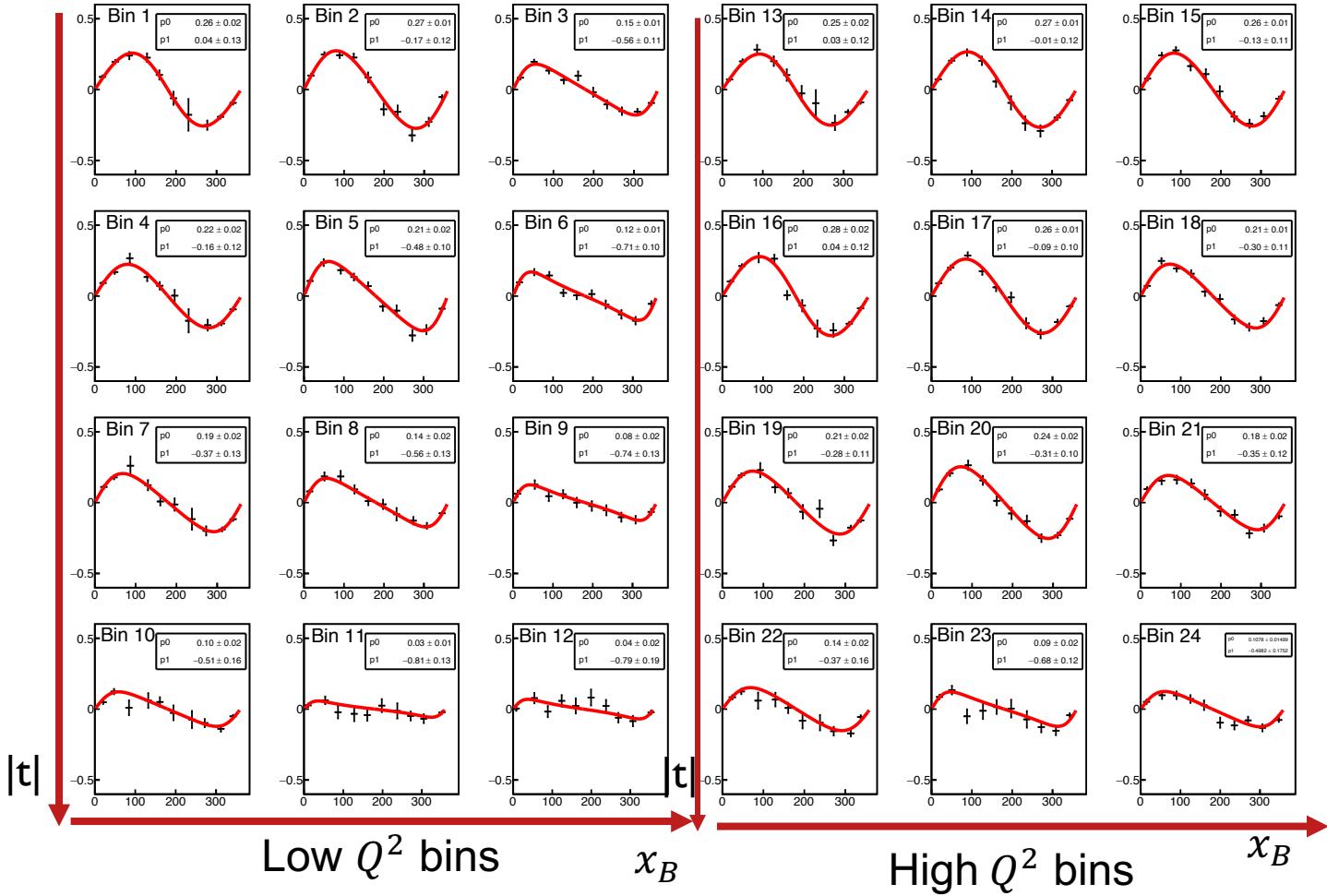
P Polarization

N^\pm number of DVCS events with helicity \pm

Statistical uncertainties only

Fit function:

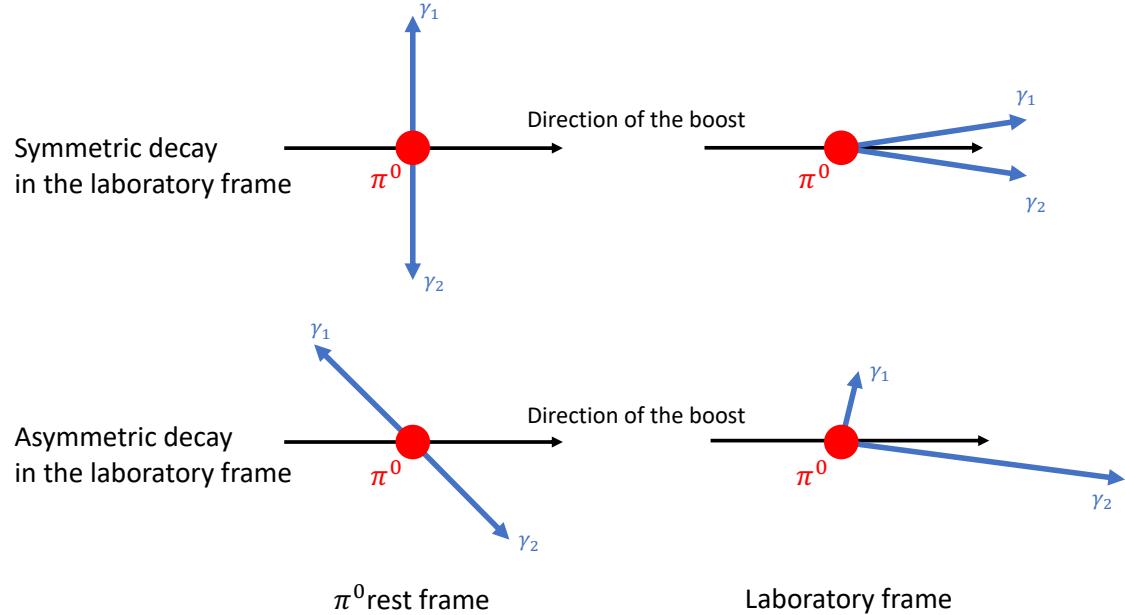
$$\frac{A \sin \varphi}{1 + B \cos \varphi}$$



3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)

- π^0 electroproduction: $ep \rightarrow ep\pi^0$
- π^0 decays very quickly into two photons (branching ratio $\sim 99\%$):
$$ep \rightarrow ep\pi^0 \rightarrow ep \gamma\gamma$$
- Asymmetric π^0 decay:
 - mimics DVCS event
 - can pass DVCS exclusivity cuts



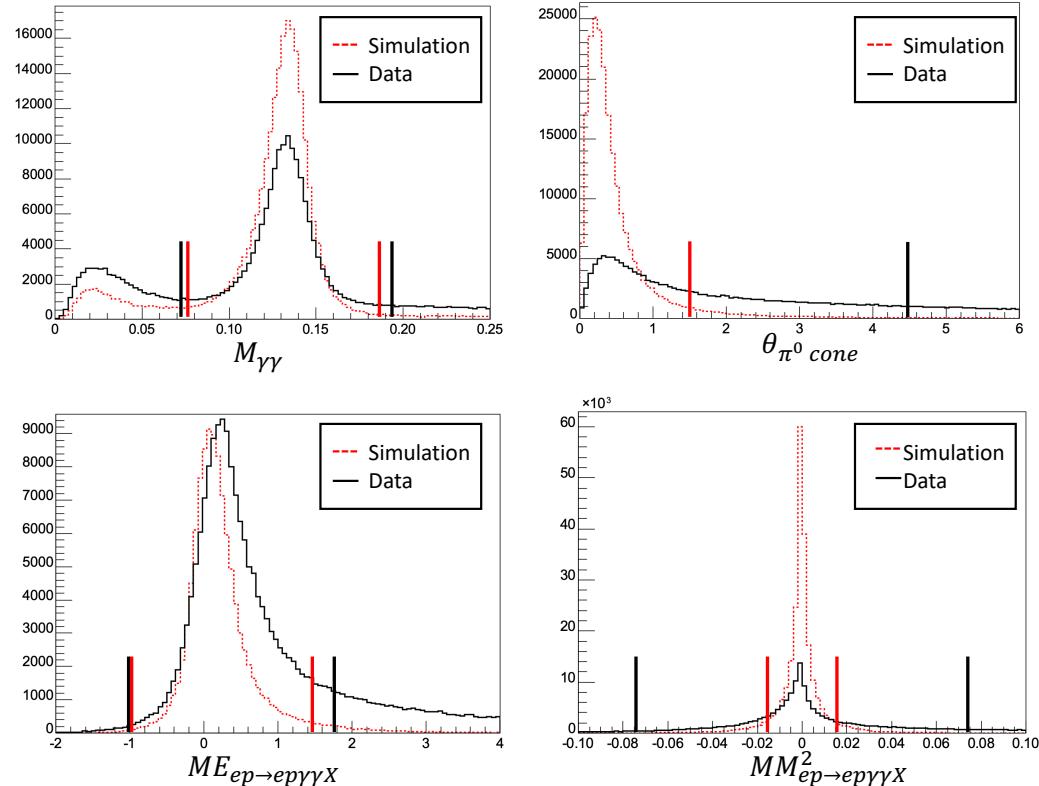
3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)

3.1 – Selection of π^0 electroproduction events

- **π^0 invariant mass**
(mass of the two photons)
- **π^0 cone angle**
(angle between measured π^0 (from the two photons and exclusive missing π^0)
- **Missing energy** $ep \rightarrow ep\gamma\gamma X$
- **Squared missing mass** $ep \rightarrow ep\gamma\gamma X$

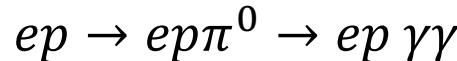
Cuts based on the simulation and scaled in the data based on the resolution



After applying all other exclusivity cuts

3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)



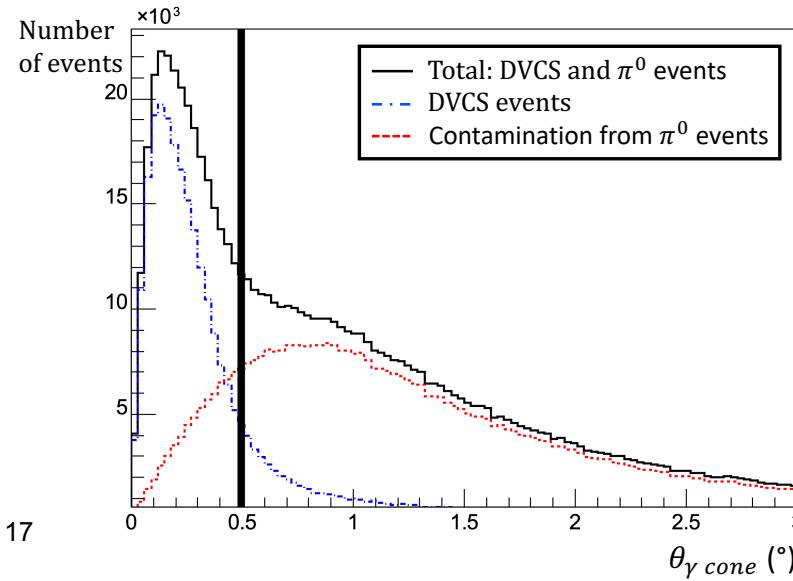
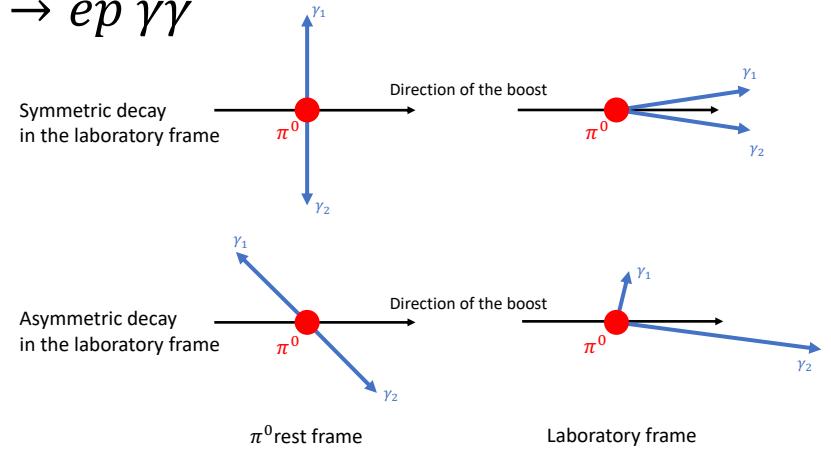
- Asymmetric π^0 decay:

- mimics DVCS event

- can pass DVCS exclusivity cuts

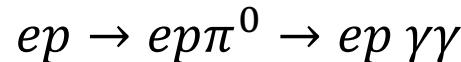
- **may not be identified as a π^0 event
(if only one photon is reconstructed)**

→ Remaining π^0 background called **contamination**
→ **Not small**



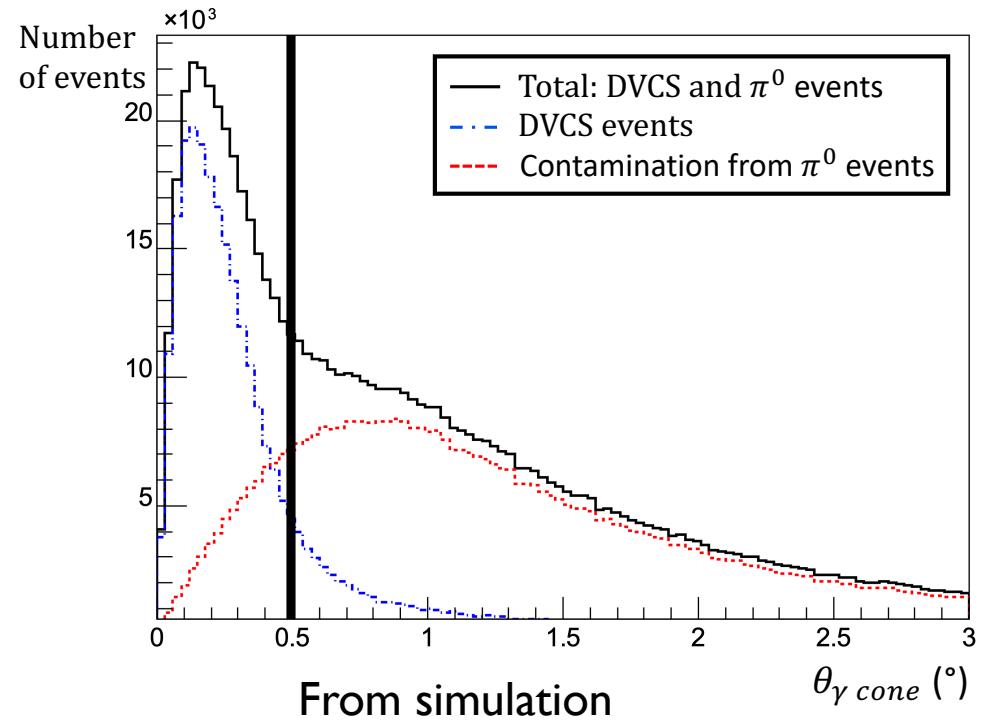
3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)



- Asymmetric π^0 decay:

- can pass DVCS exclusivity cuts
 - may not be identified as a π^0 event
(if only one photon is reconstructed)
- Remaining π^0 background called contamination
Not small



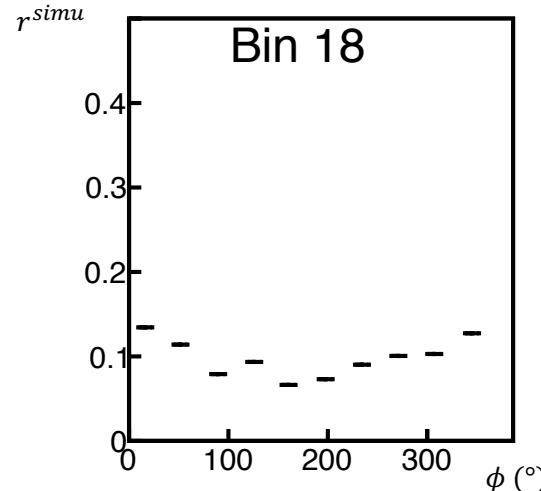
3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)

3.2 – Estimation of background

- π^0 contamination in a kinematic bin i : $n_{\pi^0, cont}(i) = r(i) n_{\pi^0, id}(i)$
- $r(i)$ is interpreted as the ratio between “size” of the phase space for π^0 decays detected as DVCS and for π^0 decays detected as π^0
- We assume that the simulation is good enough to have: $r(i) = r^{simu}(i)$
- In a π^0 simulation,
we compute:

$$r^{simu}(i) = \frac{n_{\pi^0, cont}^{simu}(i)}{n_{\pi^0, id}^{simu}(i)}$$

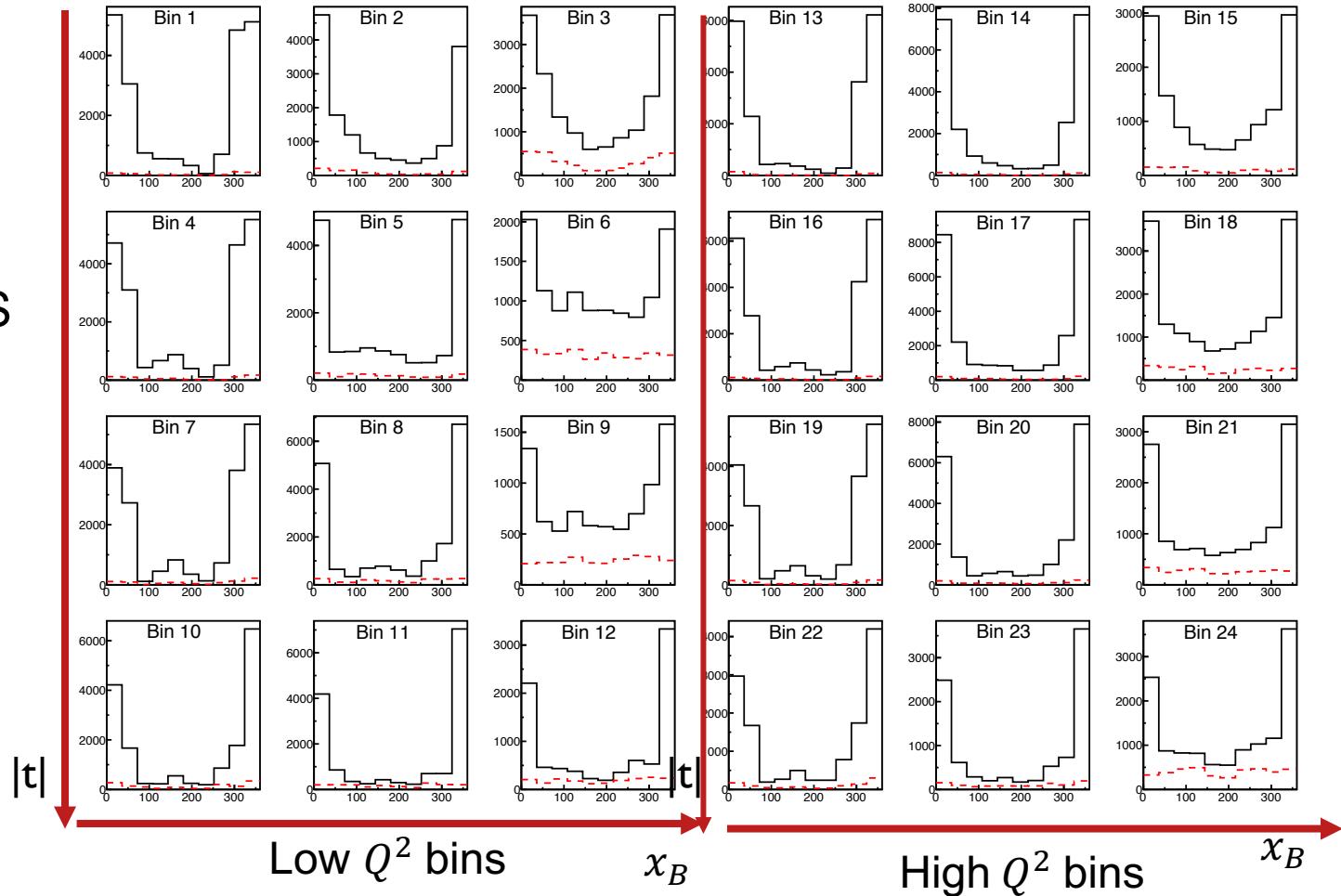


3 - Background subtraction (π^0)

3 - Background subtraction (π^0 electroproduction)

Black: total signal selected by DVCS exclusivity cuts

Red: estimated π^0 contamination

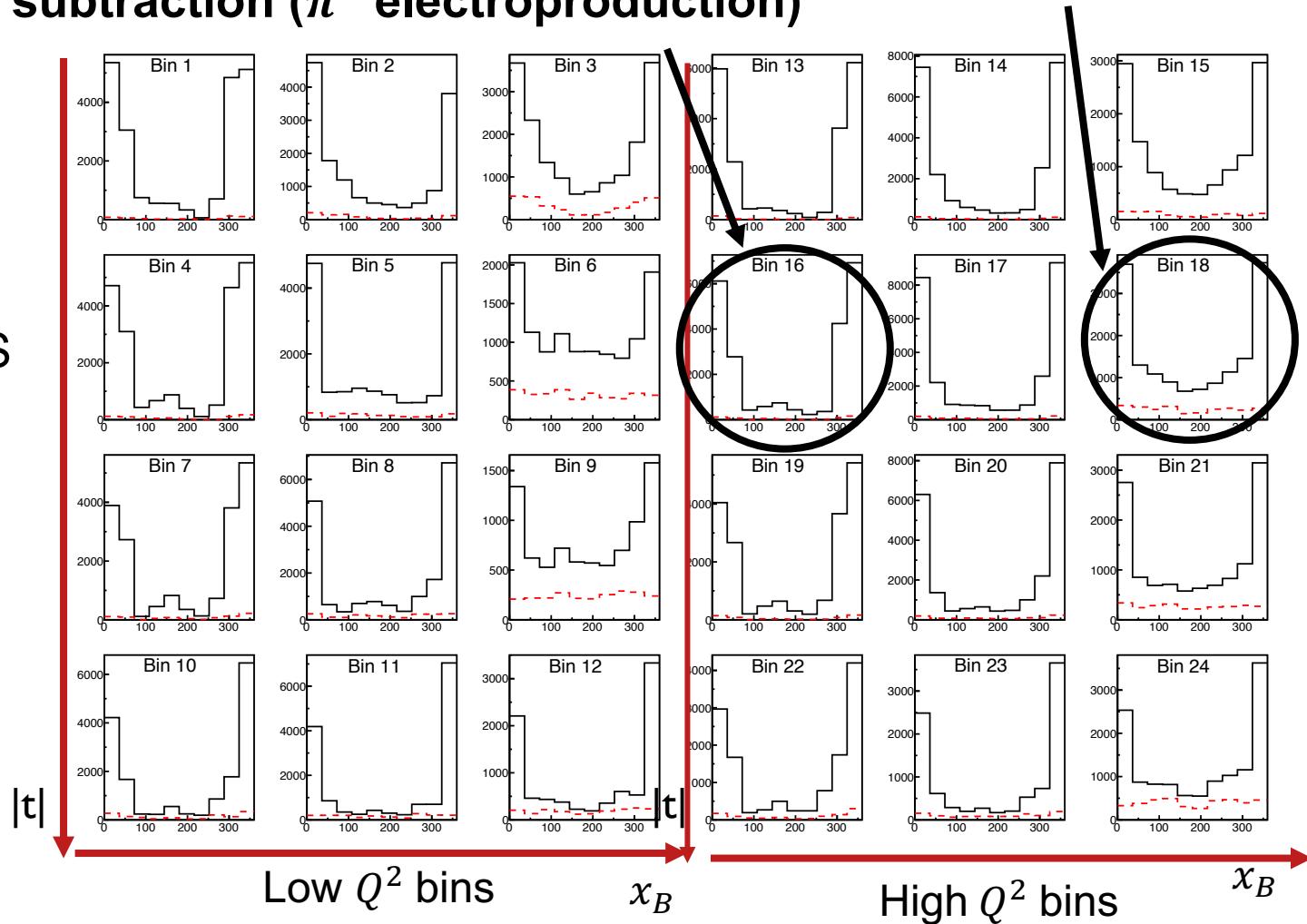


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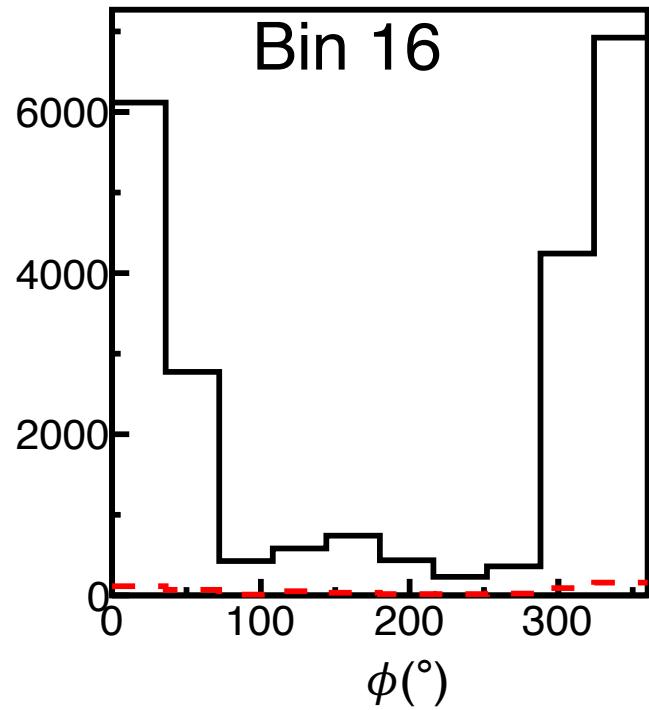


3 - Background subtraction (π^0)

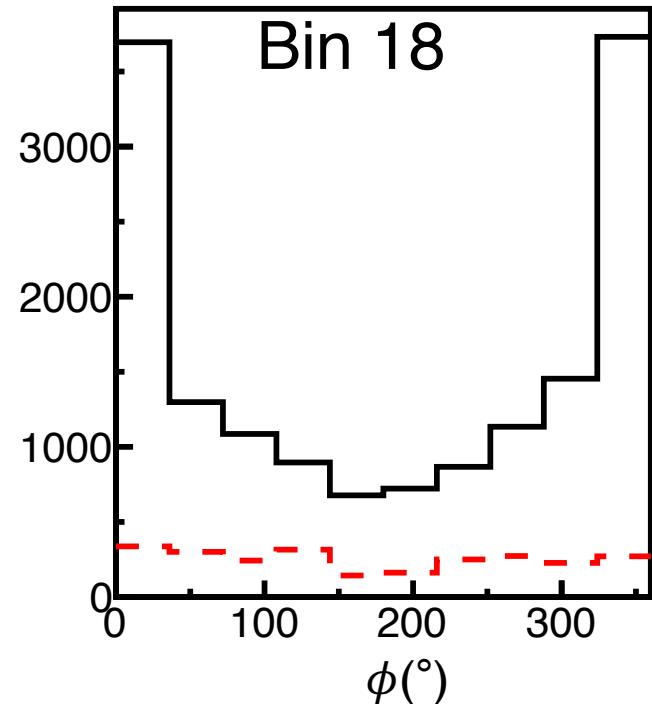
3 - Background subtraction (π^0 electroproduction)

Black: total signal selected by DVCS exclusivity cuts

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Low x_B



High x_B

3 - Background subtraction (π^0)

π^0 corrected asymmetry:

BSA for each bin:

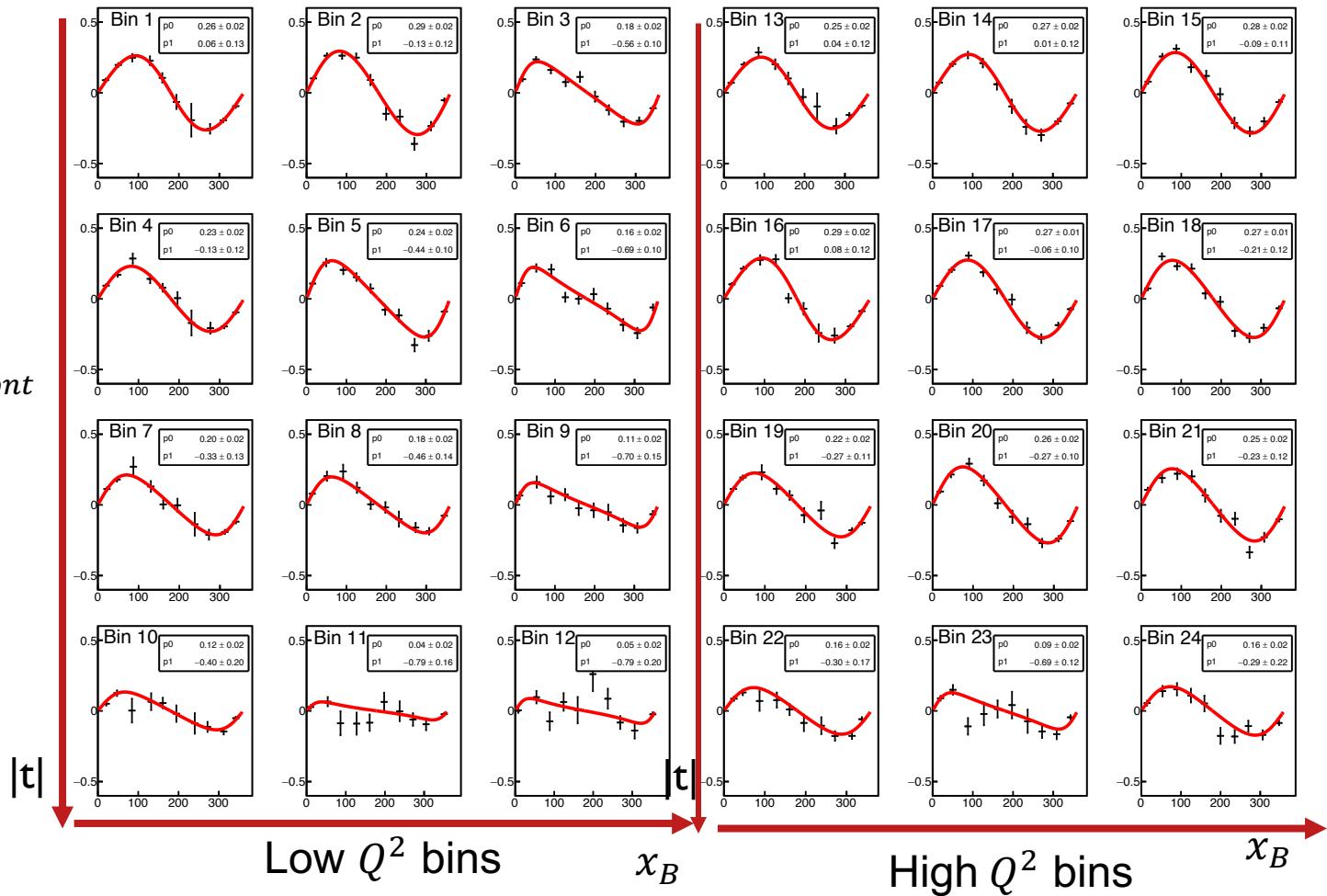
$$A_{LU} = \frac{1}{P} \frac{N^+ - N^-}{N^+ + N^-}$$

P Polarization

$$N^\pm = n_{DVCS,id}^\pm - n_{\pi^0,cont}^\pm$$

corrected number of events with helicity \pm

Statistical uncertainties only



4 - Bin migration correction

4 - Bin migration correction

Correct for events that are generated in bin j but reconstructed in bin i

We note:

- $m_{j \rightarrow i}$ number of events generated in bin j but reconstructed in bin i
- $A_{corr}(j \rightarrow i)$ BSA of events from bin j but reconstructed in bin i
 $A_{corr}(i \rightarrow i) = A_{corr}(i)$ to simplify the notation
- $A_{\pi^0 corr}(i)$ BSA of all the events reconstructed in bin i (after π^0 correction)

We have: $A_{LU, \pi^0 corr}(i) = m_{i \rightarrow i} A_{LU, corr}(i \rightarrow i) + \sum_{bin j \neq i} m_{j \rightarrow i} A_{LU, corr}(j \rightarrow i)$

So:
$$A_{corr}(i) = \frac{A_{\pi^0 corr}(i) - \sum_{bin j \neq i} m_{j \rightarrow i} A_{corr}(j \rightarrow i)}{m_{i \rightarrow i}}$$

4 - Bin migration correction

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Correct for events that are generated in bin j but reconstructed in bin i

$$A_{corr}(i) = \frac{A_{\pi^0 corr}(i) - \sum_{bin \ j \neq i} m_{j \rightarrow i} A_{corr}(j \rightarrow i)}{m_{i \rightarrow i}}$$

We estimate $A_{corr}(i)$ with:

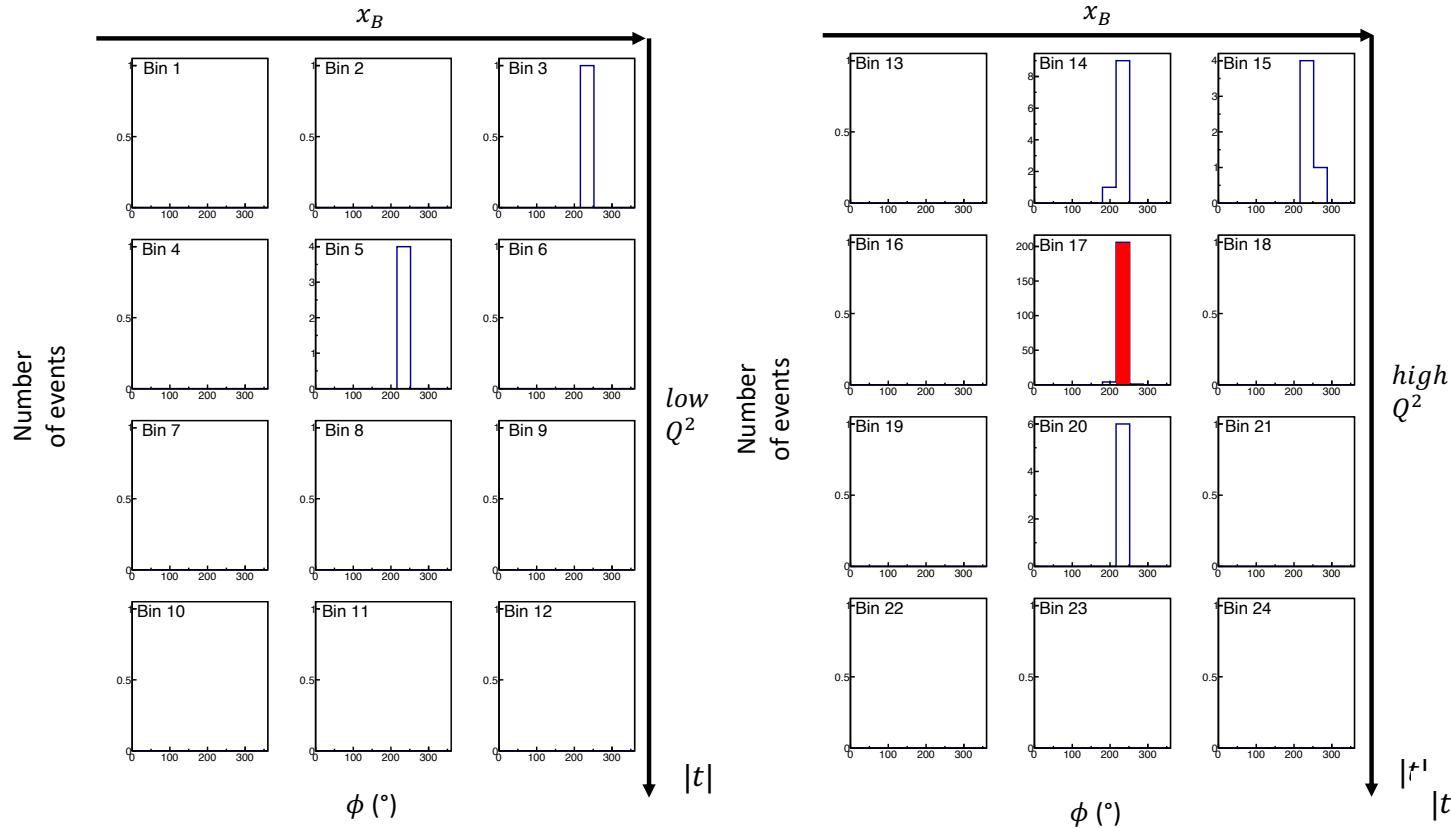
- $A_{corr}(j \rightarrow i)$ estimated by taking averaging $A_{\pi^0 corr}(i)$ and $A_{\pi^0 corr}(j)$ since this is, at the first order, the asymmetry of events coming from the edge of bin j
- $m_{j \rightarrow i}$ estimated from a simulation

4 - Bin migration correction

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We estimate $A_{corr}(i)$ with:

- $m_{j \rightarrow i}$ estimated from a simulation



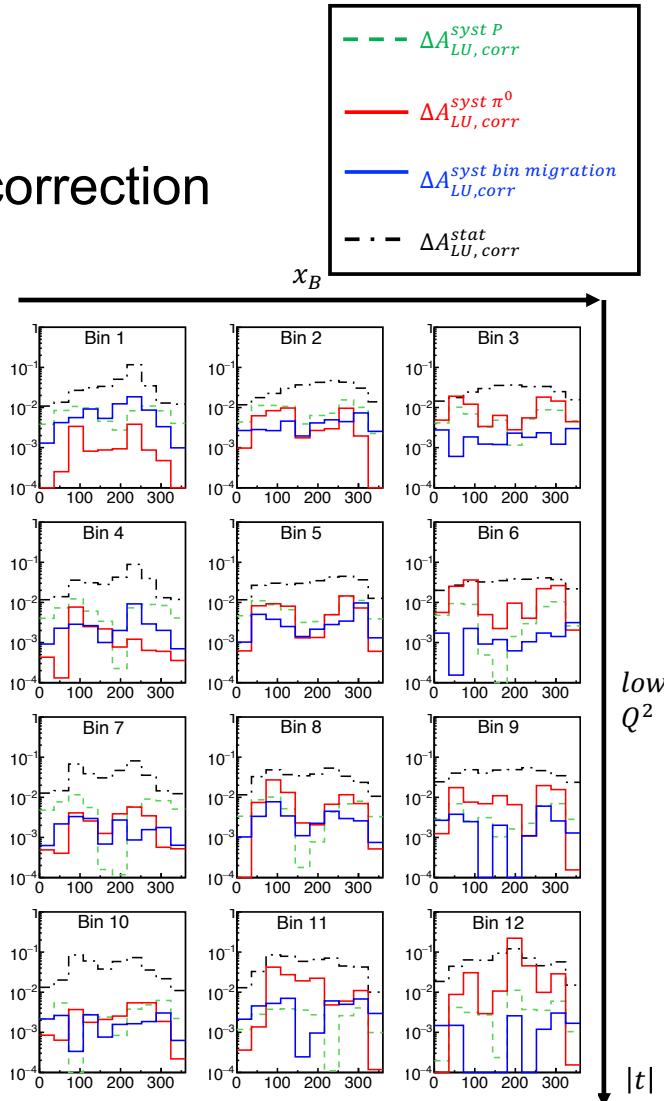
5 - Estimation of uncertainties

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Statistical uncertainties propagated after the π^0 correction
~1 - 10%. (absolute uncertainty)

Systematic uncertainties associated with:

- π^0 subtraction: contamination fraction
~ 0.1 to 7%. (absolute uncertainty)
- Bin migration: estimation of the migration and asymmetries
~ 0.1 to 2%. (absolute uncertainty)
- Polarization: polarization measurement
~ 0.1 to 2%. (absolute uncertainty)



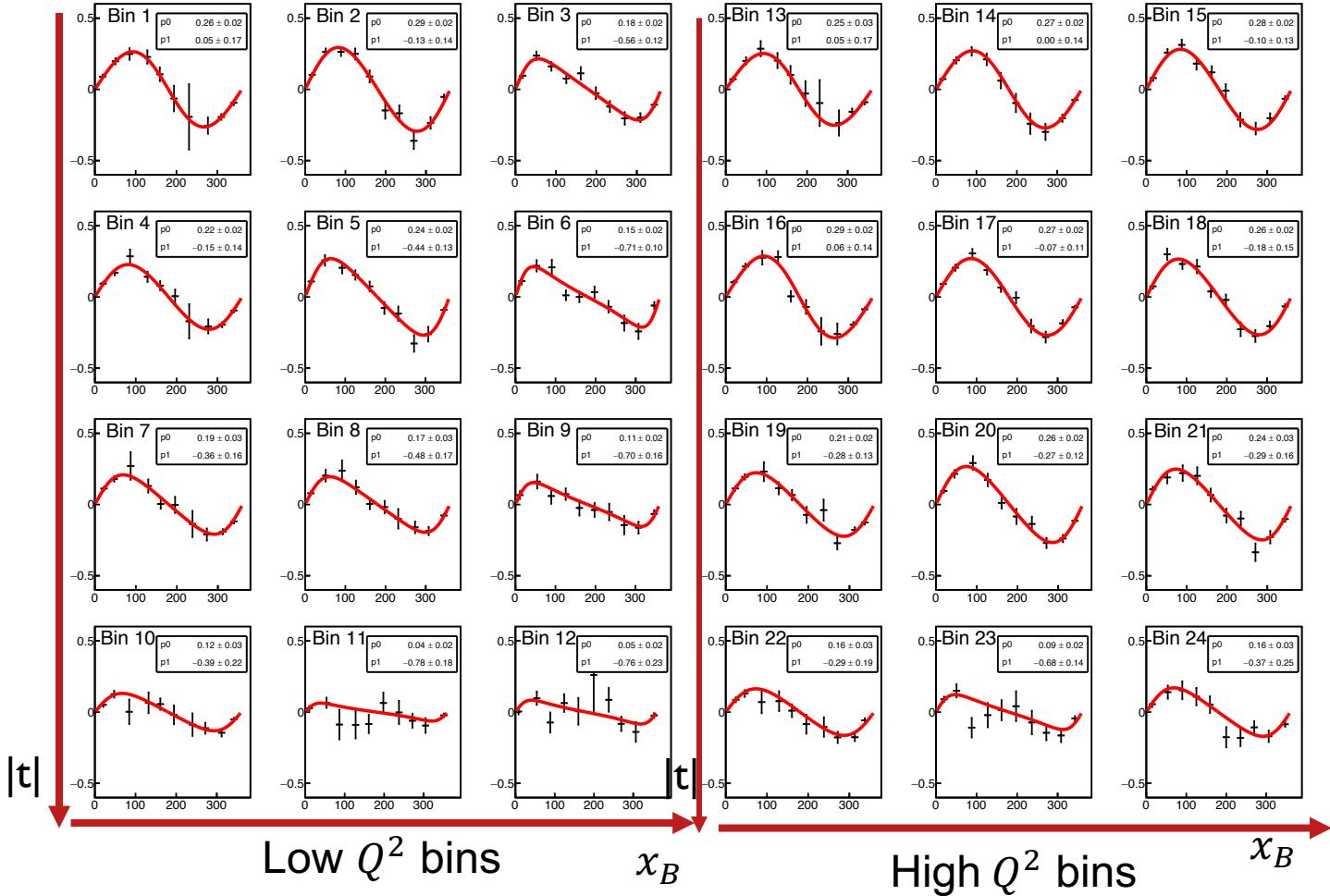
Results

Results

Statistical
and
systematic
uncertainties
added
quadratically

Fit function:

$$\frac{A \sin \varphi}{1 + B \cos \varphi}$$

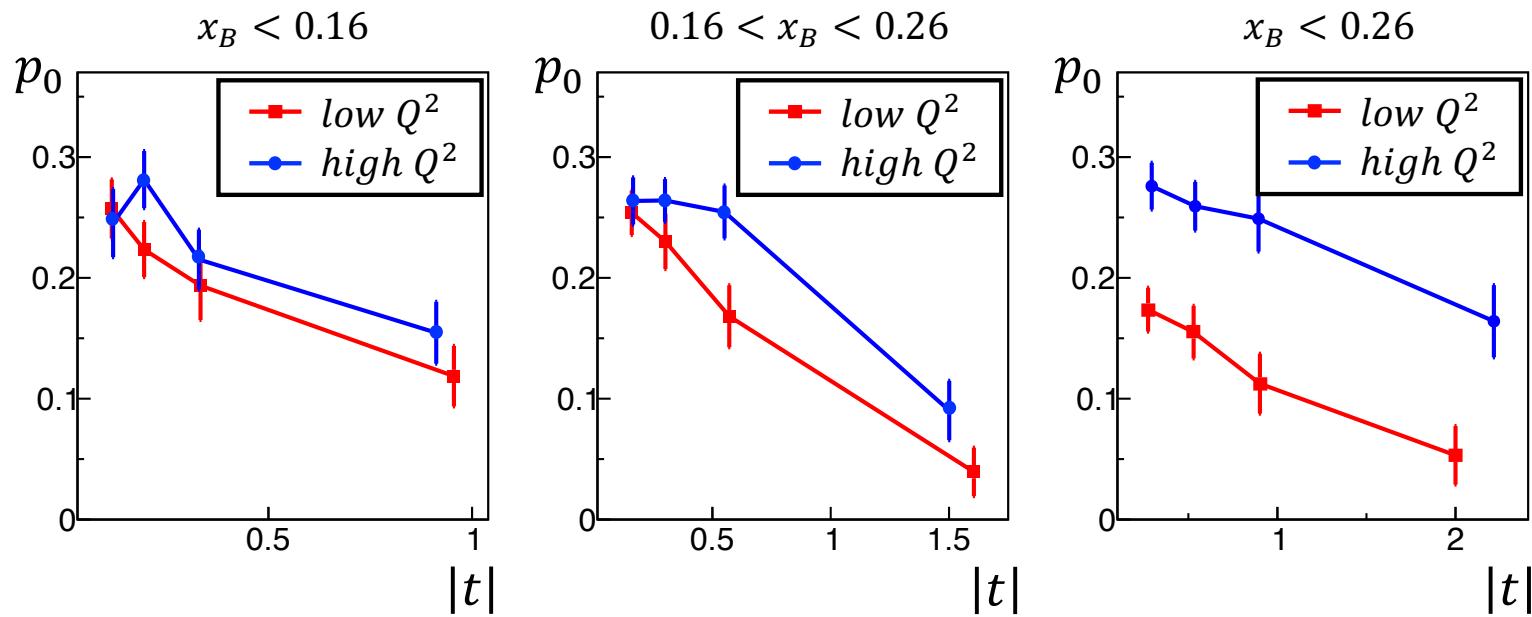


Results

Results

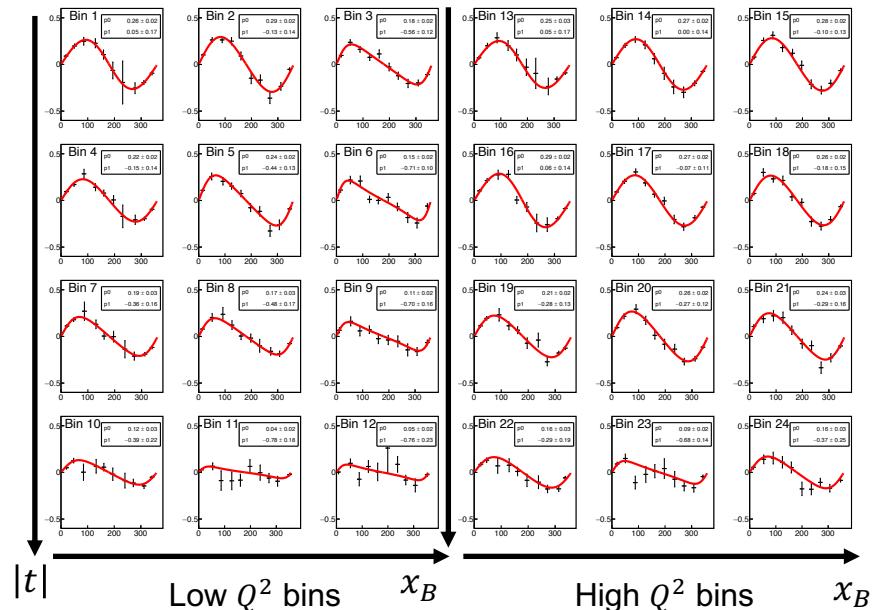
- Amplitude decreases with $|t|$
- Amplitude increases with Q^2

Careful with binning effects (difficult to provide 1-dimensional information)



Summary and outlook

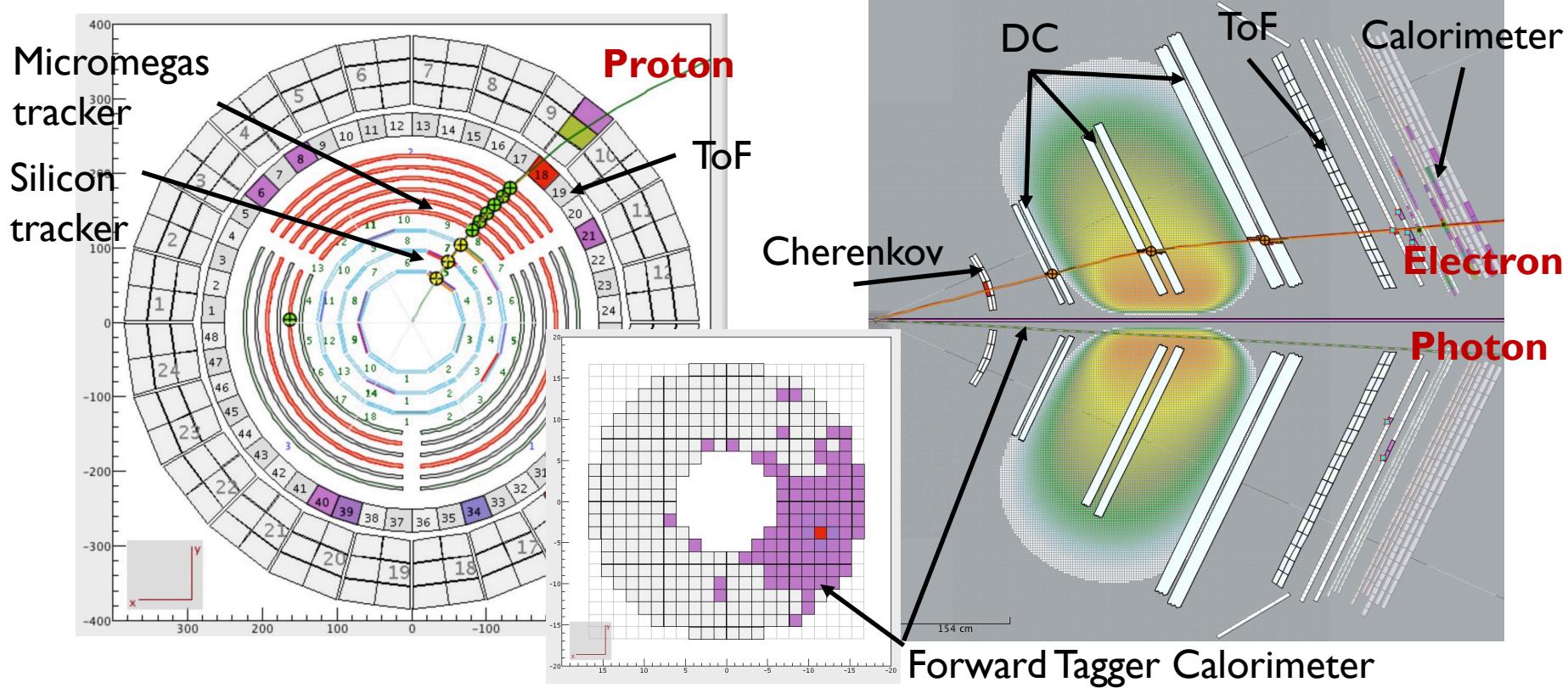
- Beam-spin asymmetry off the proton at 10.6 GeV
- Refinement of the π^0 correction still ongoing, mainly by Maxime Defurne (CEA Saclay):
 - Understanding of calorimeters and photon reconstruction
 - Comparison with other π^0 subtraction methods
- Refinement of the estimation of uncertainties, in particular related to the π^0 correction



DVCS event in CLAS12

Typical DVCS event:

- Electron in the forward detector (torus, DC, ToF, Cherenkov, Calorimeter)
- Photon in the forward tagger (calorimeter)
- Proton in the central detector (solenoid, Silicon, Micromegas and ToF)



0 - Pre-selection of events

0 - Pre-selection of events

To deal with combinatorics:

Selection of best proton and best photon candidates based their “distance” to an ideal DVCS event (using exclusivity variables)

- Compute distance to an ideal DVCS events for each kinematic variable and for each event i

$$d^i = \frac{(x^i - x_{expected}^i)^2}{(\eta^i)^2}$$

- Sum all the distances

$$d = \sum_{i=variables} d^i$$

- In each event, select the particles that have the smallest distance

Generator DVCS + π^0

Generator DVCS and π^0

- Generate DVCS and π^0 events following DVCS and π^0 cross-section
- This is a sampling problem: here we use Metropolis-Hastings algorithm
- We note x_i the points of the phase space

$$x_i = (Q^2, x_B, t, \phi)$$

- We note f the function that we want to sample: here we use

$$f = \sigma_{DVCS} + \sigma_{\pi^0}$$

we sample the sum of cross-sections

Generator DVCS + π^0

Generator DVCS and π^0 using Metropolis-Hastings algorithm

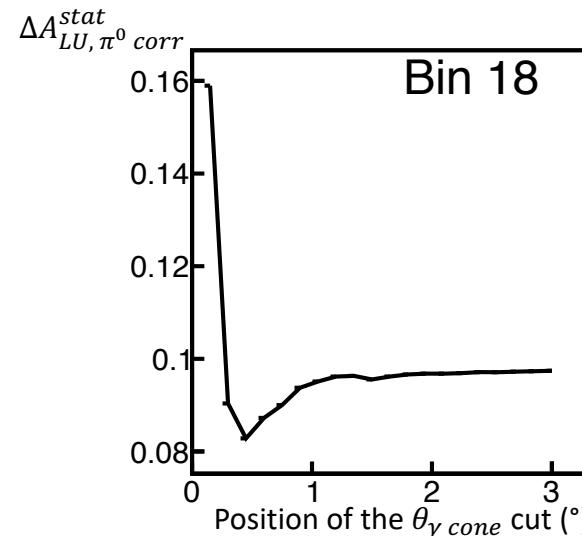
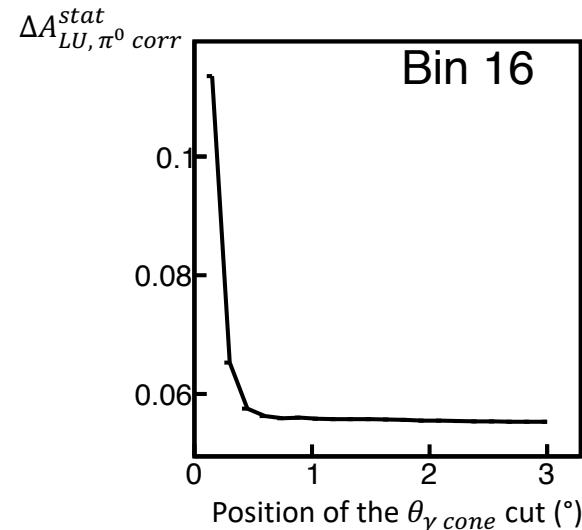
- Generate point $i + 1$ $x_{i+1, \text{proposed}} = x_i + \mathcal{Gaus}(x_i, \sigma)$
- Accept or reject the point $\alpha = \frac{f(x_{i+1, \text{proposed}})}{f(x_i)}$
 $A = \mathcal{Uniform}(0, 1)$
$$\begin{cases} \text{if } A < \alpha, x_{i+1} = x_{i+1, \text{proposed}} \\ \text{if } A > \alpha, x_{i+1} = x_i \end{cases}$$
- Choose DVCS or π^0 $B = \mathcal{Uniform}(0, f(x_{i+1}))$
$$\begin{cases} \text{if } B < \sigma_{DVCS}, \text{ generated a DVCS event} \\ \text{if } B > \sigma_{DVCS}, \text{ generate a } \pi^0 \text{ event} \end{cases}$$

2 - Selection of exclusive DVCS events

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Return on DVCS exclusivity:
optimization of the DVCS
exclusivity selection
based on the contamination

- **Optimize the position
of the cut to minimize the
uncertainty DVCS + π^0**
- Here photon cone angle with wide
exclusivity cuts

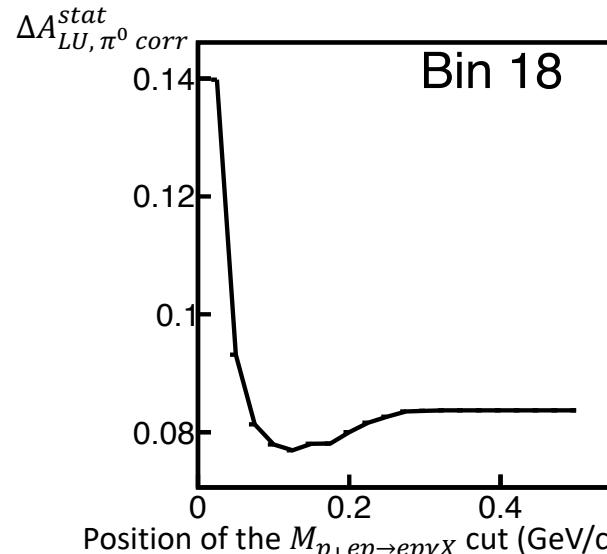
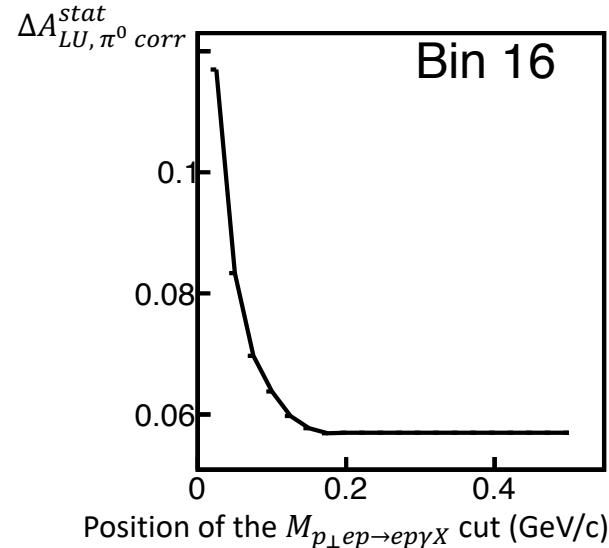


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Return on DVCS exclusivity:
optimization of the DVCS
exclusivity selection
based on the contamination

- **Optimize the position of the cut to minimize the uncertainty DVCS + π^0**
- Here missing transverse momentum with wide exclusivity cuts and the optimized photon cone angle cut

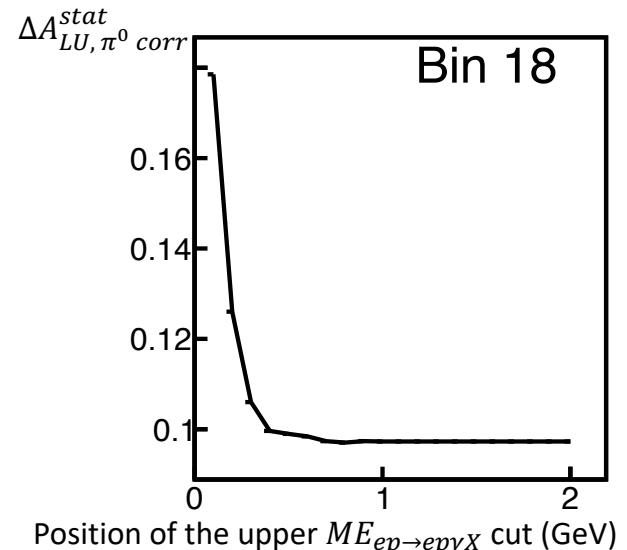
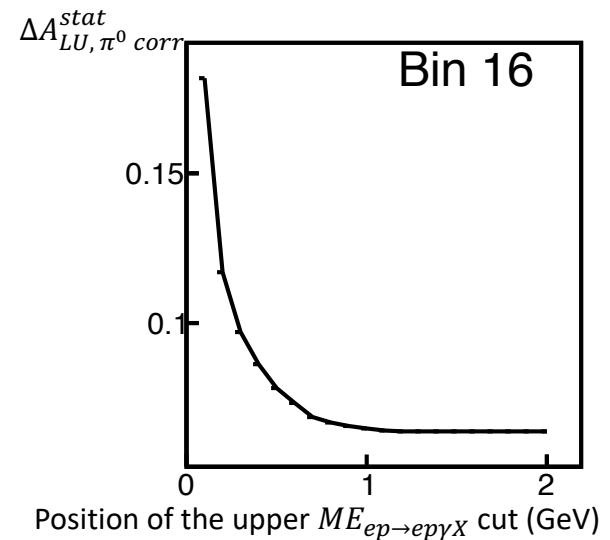


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Return on DVCS exclusivity:
optimization of the DVCS
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based on the contamination

- **Optimize the position of the cut to minimize the uncertainty DVCS + π^0**
- Here missing energy with wide exclusivity cuts and the optimized photon cone angle and missing transverse momentum cut

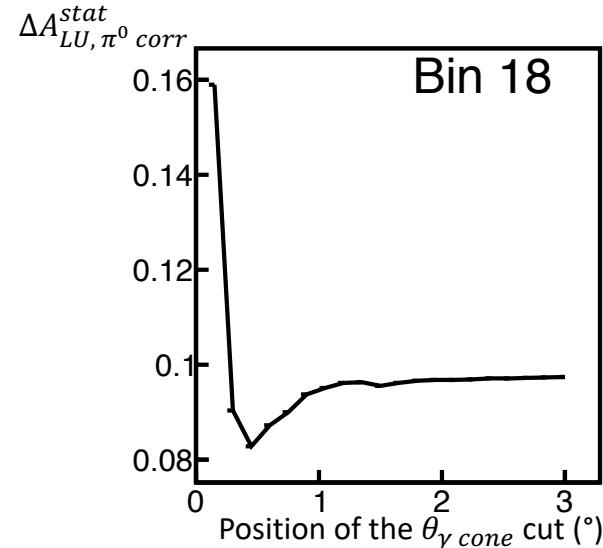
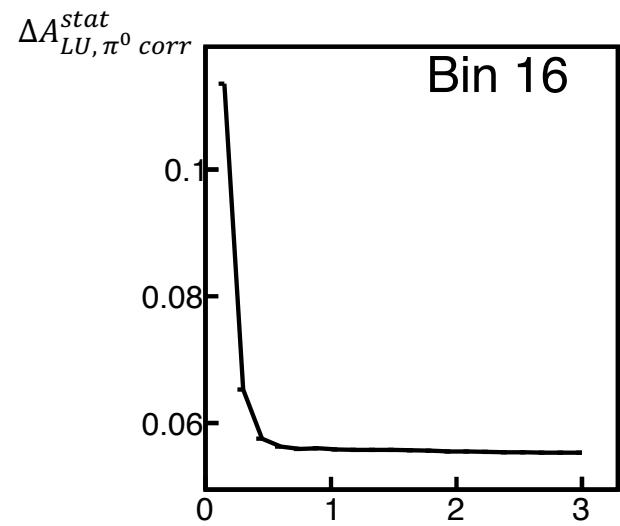


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Return on DVCS exclusivity:
optimization of the DVCS
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- **Optimize the position of the cut to minimize the uncertainty DVCS + π^0**
- Here missing energy with wide exclusivity cuts



5 - Estimation of uncertainties

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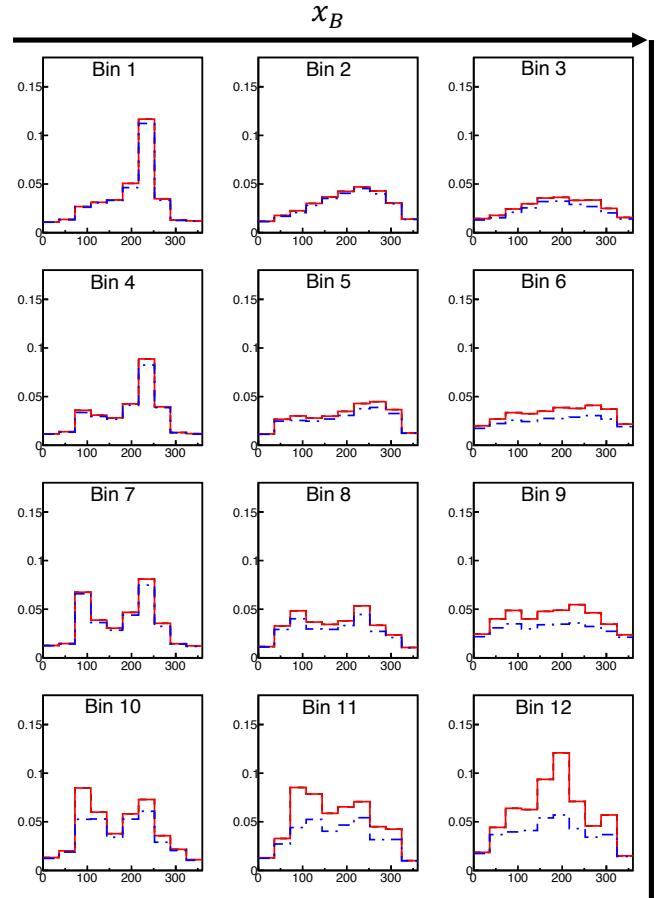
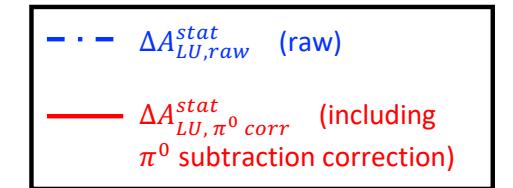
Statistical uncertainties propagated after the π^0 correction

$$\Delta A_{LU, \pi^0 corr}^{stat}(i) = \frac{2}{P} \frac{\sqrt{\left[N_{\pi^0 corr}^-(i) \Delta N_{\pi^0 corr}^+(i) \right]^2 + \left[N_{\pi^0 corr}^+(i) \Delta N_{\pi^0 corr}^-(i) \right]^2}}{\left[N_{\pi^0 corr}^+(i) + N_{\pi^0 corr}^-(i) \right]^2}$$

$$N_{\pi^0 corr}^\pm(i) = \frac{1}{C^\pm} \left[n_{ep\gamma, id}^\pm(i) - n_{\pi^0, cont}^\pm(i) \right]$$

$$= \frac{1}{C^\pm} \left[n_{ep\gamma, id}^\pm(i) - r(i) n_{\pi^0, id}^\pm(i) \right]$$

$$\Delta N^\pm(i) = \frac{1}{C^\pm} \left[\sqrt{n_{ep\gamma, id}^\pm(i) + r(i)^2 n_{\pi^0, id}^\pm(i)} + \left[n_{\pi^0, id}^\pm(i) \Delta r(i) \right]^2 \right]$$



5 - Estimation of uncertainties

5 - Estimation of uncertainties

Systematic uncertainties associated with:

- π^0 subtraction: contamination fraction
~ 0.1 to 7%. (absolute uncertainty)

$$\text{Contamination: } f(i) = \frac{n_{\pi^0, cont}(i)}{n_{ep\gamma, id}(i)}$$

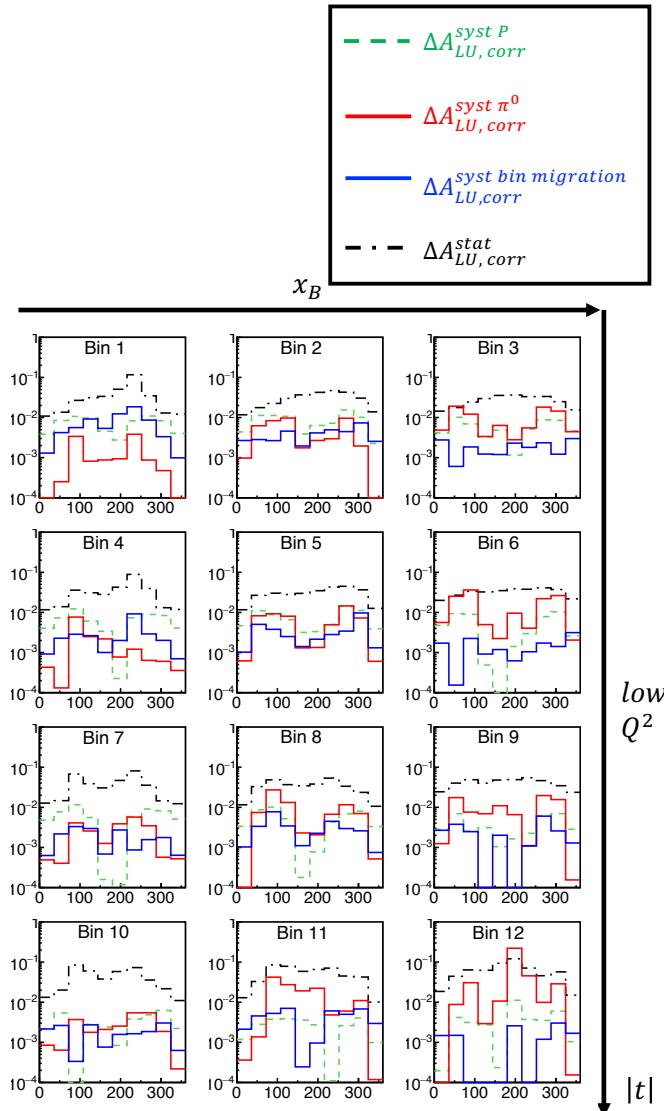
Asymmetry decomposition:

$$A_{LU, \pi^0 corr}(i) = \frac{A_{LU, raw}(i) - f(i) A_{LU, \pi^0, cont}(i)}{1 - f(i)}$$

Systematic uncertainty:

$$\Delta A_{LU, \pi^0 corr}^{syst}(i) = \frac{A_{LU, raw}(i) - f(i) A_{LU, \pi^0, cont}}{\left[1 - f(i)\right]^2} \Delta f(i)$$

Uncertainty on contamination $\Delta f(i) = 0.3 f(i)$



5 - Estimation of uncertainties

5 - Estimation of uncertainties

Systematic uncertainties associated with:

- Bin migration: estimation of the migration and asymmetries
~ 0.1 to 2%. (absolute uncertainty)

Asymmetry decomposition:

$$A_{corr}(i) = \frac{A_{\pi^0 corr}(i) - \sum_{bin j \neq i} m_{j \rightarrow i} A_{corr}(j \rightarrow i)}{m_{i \rightarrow i}}$$

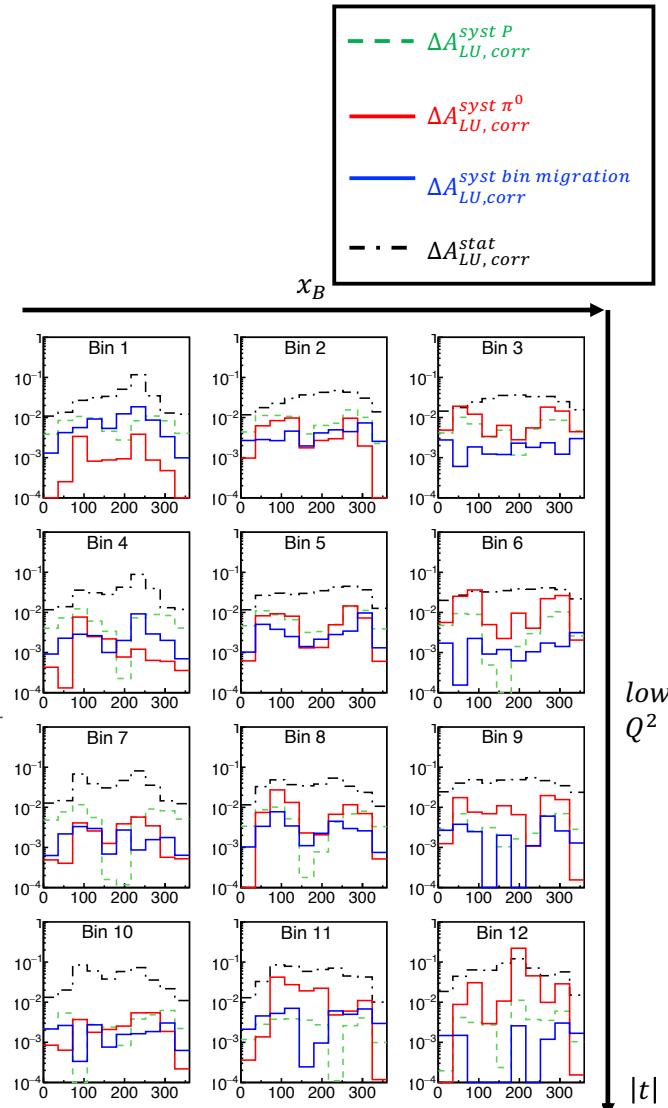
Systematic uncertainty:

$$\Delta A_{LU,corr}^{syst bin migration}(i) = \sqrt{\sum_{j \neq i} \left[\left(\frac{(-m_{i \rightarrow i} A_{corr}(j \rightarrow i) + A_{\pi^0 corr}(i) - \sum_{j \neq i} m_{j \rightarrow i} A_{corr}(j \rightarrow i)) \Delta m_{j \rightarrow i}}{m_{i \rightarrow i}^2} \right)^2 + \left(\frac{-m_{j \rightarrow i}}{m_{i \rightarrow i}} \Delta A_{corr}(j \rightarrow i) \right)^2 \right]}$$

Uncertainty on contamination

$$\Delta m_{j \rightarrow i} = 0.1 m_{j \rightarrow i}$$

$$\Delta A_{LU,corr}(j \rightarrow i) = \frac{|A_{LU,\pi^0 corr}(i) - A_{LU,\pi^0 corr}(j)|}{2}$$



5 - Estimation of uncertainties

5 - Estimation of uncertainties

Systematic uncertainties associated with:

- Polarization: polarization measurement
~ 0.1 to 2%. (absolute uncertainty)

$$\Delta A_{LU\,corr}^{syst\,P}(i) = \frac{A_{LU\,corr}}{P} \Delta P$$

